

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|------|---|---|------------------|---------|------------------|
| L1 | 0 | fuse same semiconductor same locat\$4 same memory same (defect\$4fail\$4) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT | OR | ON | 2005/04/15 13:54 |
| L2 | 106 | fuse same semiconductor same locat\$4 same memory same (defect\$4 fail\$4) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT | OR | ON | 2005/04/15 13:54 |
| L3 | 62 | semiconductor same fuse with locat\$4 same memory same (defect\$4 fail\$4) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT | OR | ON | 2005/04/15 13:55 |
| L4 | 2457 | test\$4 with fuses!3 same semiconductor | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT | OR | ON | 2005/04/15 13:55 |
| L5 | 371 | test\$4 with fuses! same semiconductor | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT | OR | ON | 2005/04/15 13:56 |
| L6 | 15 | test\$4 with fuses! same semiconductor and memory same location same defect\$4 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT | OR | ON | 2005/04/15 13:58 |
| L7 | 3 | test\$4 near fuses! same semiconductor and memory same location same defect\$4 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT | OR | ON | 2005/04/15 13:59 |
| L8 | 14 | test\$4 near fuses! same semiconductor and memory same fuse same defect\$4 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT | OR | ON | 2005/04/15 13:59 |
| L9 | 12 | test\$4 near fuses! same semiconductor and memory same fuse same defect\$4 and fuse.ti. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT | OR | ON | 2005/04/15 13:59 |